

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/617,029	KOMIYA ET AL.	
	Examiner	Art Unit	
	Hai C. Pham	2861	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
347	239, 255	11/18/2005	HP
PGPub Text Search		11/18/2005	HP